

## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number  
2501082-991101Application Number  
10/672,056Applicant  
Rajeshwar Chhibber et al.Filing Date  
September 25, 2003Group Art  
Unit

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

## OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

MS	IBM Technical Disclosure Bulletin, "Contamination Particle Detection and Location", <i>Mechanical Devices DMB</i> , pp. 1230-1231 (Sept 1976).
MS	IBM Technical Disclosure Bulletin, "System for dynamic matching to film", <i>Data Recognition JJ</i> , pp. 150-151 (July 1968)
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

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PATENT DISCLOSURE

(Use several sheets if necessary)

**Application Number**  
**10/672,056**

Filing Date	September 25, 2003	Group Art Unit
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<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)				Docket Number 2501082-091101		Application Number 10/672,058							
				Applicant Rajeshwar Chhibber et al.									
				Filing Date September 25, 2003		Group Art Unit 2877							
<b>U.S. PATENT DOCUMENTS</b>													
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EXAMINE R INITIAL	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
<b>OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)</b>													

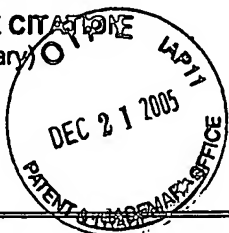
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Form PTO-1449	U.S. DEPT. OF COMMERCE Patent and Trademark Office	Attorney Docket Number:  357335-991120	Serial Number:  10/672,056
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		Applicant: Rajeshwar Chhibber	
		Filing date: September 25, 2003	Group art unit: 2877



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Examiner Initial	Patent number	Date	Name	Class	Sub-class	Filing date if appropriate

### FOREIGN PATENT DOCUMENTS

Examiner Initial	Document number	Date	Country	Class	Sub-class	Translation	
						YES	NO

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<i>MS</i>	International Search Report mailed November 2, 2005 for International Patent No. PCT/US03/31071 filed 26 Sept 2003
Examiner: <i>Michael Stahn</i>	Date Considered: <i>2-28-06</i>
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP '609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.	